

STEF12

Datasheet

Electronic fuse for 12 V line



DFN10L (3x3 mm)

Features

- Continuous current (typ): 3.6 A
- N-channel on-resistance (typ): 53 mΩ
- Enable/Fault functions
- Output clamp voltage (typ): 15 V
- Undervoltage lockout
- Short-circuit limit
- Overload current limit
- Controlled output voltage ramp
- Thermal latch (typ): 165 °C
- Operating junction temp. 40 °C to 125 °C
- Available in DFN10 (3x3 mm) package

Applications

- Hard disk drives
- Solid state drives (SSD)
- Hard disk and SSD arrays
- Set-top boxes
- DVD and Blu-ray disc drivers

Description

The STEF12 is an integrated electronic fuse optimized for monitoring output current and input voltage. Connected in series to a 12 V rail, it is capable of protecting the electronic circuitry on its output from overcurrent and overvoltage. The device has a controlled delay and turn-on time.

When an overload condition occurs, the STEF12 limits the output current to a predefined safe value. If the anomalous overload condition persists it goes into an open state, disconnecting the load from the power supply. If a continuous short-circuit is present on the board, when power is re-applied the E-fuse initially limits the output current to a safe value and then again goes into an open state.

The device is equipped with a thermal protection circuit. The intervention of the thermal protection is signal led to the board monitoring circuits through a signal on the Fault pin.

Unlike the mechanical fuses, which must be physically replaced after a single event, the Efuse does not degrade in its performance after short-circuit/thermal protection interventions and it is reset either by recycling the supply voltage or using the Enable pin.

The companion chip for the 5 V power rails is also available with part number STEF05.

Maturity status link

STEF12

1 Device block diagram

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Figure 1. Block diagram

2 Pin configuration

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Figure 2. Pin connection (top view)



Table 1. Pin description

Pin n°	Symbol	Note
1	GND	Ground pin
2	dv/dt	The internal dv/dt circuit controls the slew rate of the output voltage at turn-on. The internal capacitor allows a ramp-up time of around 1 ms. An external capacitor can be added to this pin to increase the ramp time. If an additional capacitor is not required, this pin should be left open.
	En/Fault	The Enable/Fault pin is a tri-state, bi-directional interface. During normal operation the pin must be left floating, or it can be used to disable the output of the device by pulling it to ground using an open drain or open collector device.
3		If a thermal fault occurs, the voltage on this pin goes into an intermediate state to signal a monitor circuit that the device is in thermal shutdown. It can be connected to another device of this family to cause a simultaneous shutdown during thermal events.
4	I-Limit	A resistor between this pin and the Source pin sets the overload and short-circuit current limit levels. Don't leave this pin unconnected.
5	NC	Not connected
6 to 10	V _{OUT} /Source	Connected to the source of the internal power MOSFET and to the output terminal of the fuse
11	V _{CC}	Exposed pad. Positive input voltage must be connected to $V_{CC}.$

3 Maximum ratings

Symbol	Parameter	Value	Unit
V _{CC}	Positive power supply voltage (steady state)	-0.3 to 18	V
	Positive power supply voltage (max 100 ms)	-0.3 to 25	V
V _{OUT} /source	(max 100 ms)	-0.3 to V _{CC} +0.3	V
I-Limit	(max 100 ms)	-0.3 to 25	V
En/Fault		-0.3 to 7	V
dv/dt		-0.3 to 7	V
T _{op}	Operating junction temperature range	-40 to 125	°C
T _{STG}	Storage temperature range	-65 to 150	°C
T _{LEAD}	Lead temperature (soldering) 10 sec	260	°C

Table 2. Absolute maximum ratings

1. The thermal limit is set above the maximum thermal rating. It is not recommended to operate the device at temperatures greater than the maximum ratings for extended periods of time.

Note:

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Absolute maximum ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thJA}	Thermal resistance junction-ambient	52.7	°C/W
R _{thJC}	Thermal resistance junction-case	17.4	°C/W

Table 4. ESD performance

Symbol	Parameter	Test conditions	Value	Unit
ESD	ESD protection	HBM	2	kV
		MM	200	V
		CDM	500	V

4 Electrical characteristics

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Table 5. Electrical characteristics V_{CC} = 12 V, V_{EN} = 3.3 V, C_I = 10 μ F, C_O = 47 μ F, T_J = 25 °C (unless otherwise specified).

		otherwise specified).				
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Under/Ove	rvoltage protection					
V _{Clamp}	Output clamping voltage	V _{CC} = 18 V	13.8	15	16.2	V
V _{UVLO}	Undervoltage lockout	Turn-on, voltage rising	7.7	8.5	9.3	V
V _{Hyst}	UVLO hysteresis			0.80		V
Power MO	SFET					
t _{dly}	Delay time	Enabling of chip to $I_D = 100 \text{ mA}$ with a 1 A resistive load		350		μs
D	On registeres	(1)	35	53	70	mΩ
R _{DSon}	On-resistance	-40 °C < T _J < 125 °C ⁽²⁾			82	11122
V _{OFF}	Off state output voltage	V_{CC} = 18 V, V_{GS} = 0, R_L = infinite		40	100	mV
		0.5in ² pad, T _A = 25 °C ⁽¹⁾		3.6		
Ι _D	Continuous current	Minimum copper, T _A = 80 °C		1.7		A
Current lim	it	11				
I _{Short}	Short-circuit current limit	R _{Limit} = 22 Ω	3.3	4.4	5.5	А
I _{Lim}	Overload current limit	R _{Limit} = 22 Ω		4.4		Α
dv/dt circu	it			1	1	1
dv/dt	Output voltage ramp time	Enable to V_{OUT} = 11.7 V, No $C_{dv/dt}$	0.5	0.9	2.6	ms
Enable/Fau	llt			1	1	1
VIL	Low level input voltage	Output disabled	0.35	0.58	0.81	V
V _{I(INT)}	Intermediate level input voltage	Thermal fault, output disabled	0.82	1.4	1.95	V
VIH	High level input voltage	Output enabled	1.96	2.64	3.3	V
V _{I(MAX)}	High state maximum voltage		3.4	4.3	5.4	V
I	Low level input current (sink)	V _{Enable} = 0 V		-10	-30	μA
lj.	High level leakage current for external switch	V _{Enable} = 3.3 V			1	μA
	Maximum fan-out for fault signal	Total numbers of chips that can be connected to this pin for simultaneous shutdown			3	Units
Total devic	e	·				
I _{Bias}	Bias current	Device operational		1.5	2	mA
'Blas		Thermal shutdown		1		
V _{min}	Minimum operating voltage				7.6	V
Thermal la	tch					
T _{SD}	Shutdown temperature	(1)		165		°C

1. Pulse test: Pulse width = $300 \ \mu$ s, Duty cycle = 2%.

2. Guaranteed by design, but not tested in production.

5 Typical application

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Figure 3. Application circuit

Figure 4. Typical HDD application circuit



5.1 Operating modes

5.1.1 Turn-on

When the input voltage is applied, the Enable/Fault pin goes up to the high state, enabling the internal control circuitry.

After an initial delay time of typically 350 µs, the output voltage is supplied with a slope defined by the internal dv/dt circuitry. If no additional capacitor is connected to dv/dt pin, the total time from the Enable signal going high and the output voltage reaching the nominal value is around 1 ms (refer to Figure 5, Figure 15).

5.1.2 Normal operating condition

The STEF12 E-fuse behaves like a mechanical fuse, buffering the circuitry on its output with the same voltage shown at its input, with a small voltage fall due to the N-channel MOSFET R_{DSOn}.



5.1.3 Output voltage clamp

This internal protection circuit clamps the output voltage to a maximum safe value, typically 15 V, if the input voltage exceeds this threshold.

5.1.4 Current limiting

When an overload event occurs, the current limiting circuit reduces the conductivity of the power MOSFET, in order to clamp the output current at the value selected externally by means of the limiting resistor R_{Limit} (Figure 3).

5.1.5 Thermal shutdown

If the device temperature exceeds the thermal latch threshold, typically 165 °C, the thermal shutdown circuitry turns the power MOSFET off, thus disconnecting the load. The EN/Fault pin of the device is automatically set at an intermediate voltage, in order to signal the overtemperature event. In this condition the E-fuse can be reset either by cycling the supply voltage or by pulling down the EN pin below the V_{il} threshold and then releasing it.

5.2 R limit calculation

As shown in Figure 3, the device uses an internal N-channel sense FET with a fixed ratio, to monitor the output current and limit it at the level set by the user.

The R_{Limit} value for achieving the requested current limitation can be estimated by using the following theoretical formula, together with the graph in Figure 13.

$$R_{Limit} = \frac{95}{I_{Short}} \tag{1}$$

5.3 C_{dv/dt} calculation

Connecting a capacitor between the $C_{dv/dt}$ pin and GND allows the modification of the output voltage ramp-up time.

Given the desired time interval Δt during which the output voltage goes from zero to its maximum value, the capacitance to be added on the C_{dv/dt} pin can be calculated using the following theoretical formula:

$$C_{dv/dt} = 3.92 \times 10^{-8} \Delta t - 35.3 \times 10^{-12}$$
⁽²⁾

Where $C_{dv/dt}$ is expressed in Farads and the time in seconds.

The addition of an external $C_{dv/dt}$ influences also the initial delay time, defined as the time between the Enable signal going high and the start of the V_{OUT} slope (figure below).

The contribution of the external capacitor to this time interval can be estimated by using the following theoretical formula:

$$delay time \left[s\right] = 35 \times 10^{-5} + 71 \times 10^5 \times C_{d\nu/dt} \left[F\right]$$
(3)



Figure 5. Delay time and V_{OUT} ramp-up time

5.4 Enable/Fault pin

The Enable/Fault pin has the dual function of controlling the output of the device and, at the same time, of providing information about the device status to the application.

When it is used as a standard Enable pin, it should be connected to an external open-drain or open-collector device. In this case, when it is pulled at low logic level, it turns the output of the E-Fuse off.

If this pin is left floating, since it has internal pull-up circuitry, the output of the E-Fuse is kept ON, in normal operating conditions.

In case of thermal fault, the pin is pulled to an intermediate state (figure below). This signal can be provided to a monitor circuit, informing it that a thermal shutdown has occurred, or it can be directly connected to the Enable/ Fault pins of other STEFxx devices on the same application in order to achieve a simultaneous enable/disable feature.

When a thermal fault occurs, the device can be reset either by cycling the supply voltage or by pulling down the Enable pin below the V_{il} threshold and then releasing it.



Figure 6. Enable/Fault pin status



6 Typical characteristics



Figure 9. UVLO hysteresis vs. temperature Figure 10. Off-state voltage vs. temperature 1.4 250 V_{CC} from 12 to 0 V, R_{LIMIT} = 15 Ω V_{CC} = 18 V, V_{GS} = 0, R_L = infinite 1.2 200 1 UVLO Hysteresys (V) Output Voltage (mV) 150 0.8 100 0.6 50 0.4 0 0.2 -40 -25 0 25 55 85 125 150 -40 -25 0 25 55 85 125 150 Temperature °C Temperature °C

The following plots are referred to the typical application circuit and, unless otherwise noted, at T_A = 25 °C.







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7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

7.1 DFN10L (3x3 mm) package information



Figure 21. DFN10L (3x3 mm) package outline

Dim.	mm		
Dim.	Min.	Тур.	Max.
A	0.80	0.90	1.00
A1		0.02	0.05
A2	0.55	0.65	0.80
A3		0.20	
b	0.18	0.25	0.30
D	2.85	3.00	3.15
D2	2.20		2.70
E	2.85	3.00	3.15
E2	1.40		1.75
E3	0.230		
E4	0.365		
е		0.50	
L	0.30	0.40	0.50
ddd			0.08

Table 6. DFN10L (3x3 mm) mechanical data

Figure 22. DFN10L (3x3 mm) recommended footprint



7.2 DFN10L (3x3 mm) packing information

Figure 23. DFN10L (3x3) tape and reel outline



Table 7. DFN10L (3x3) tape and reel mechanical data

Dim.		mm	
Dini.	Min.	Тур.	Max.
A			330
С	12.8		13.2
D	20.2		
Ν	60		
Т			18.4
Ao		3.3	
Во		3.3	
Ко		1.1	
Po		4	
Р		8	

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8 Ordering information

Table 8. Order codes

Order code	Package	Packaging
STEF12PUR	DFN10 (3x3 mm)	Tape and reel

Revision history

Date	Revision	Changes
15-Jul-2011	1	Initial release.
08-Aug-2011	2	Modified definition for T _{op} in Table 3: Absolute maximum ratings.
14-Dec-2011	3	Removed $V_{d\nu/dt}$ and $I_{d\nu/dt}$ rows from dv/dt circuit Table 6 on page 6.
06-Mar-2012	4	Updated: package mechanical data Table 7 on page 17, Figure 21 on page 16 and Figure 24 on page 19.
14-Jan-2013	5	Updated: package mechanical data Table 7 on page 17 and Figure 21 on page 16.
03-Aug-2015	6	Updated Equation 2, Equation 3 and Section 7: Package information. Minor text changes.
07-Feb-2020	7	Updated Figure 17 and Figure 18.

Table 9. Document revision history

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